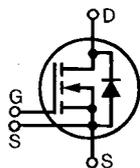
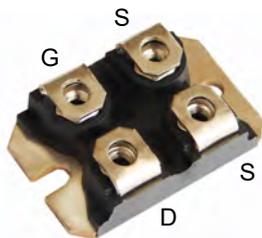


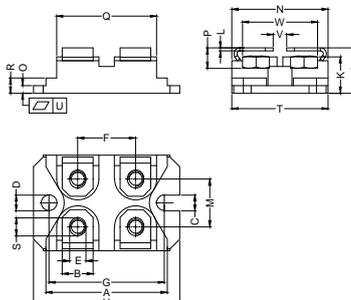
SMOS38N100S

N Channel Enhancement Mode Power MOSFETs



G=Gate, D=Drain,
S=Source

Dimensions SOT -227(ISOTOP)



Dim.	Millimeter		Dim.	Millimeter	
	Min.	Max.		Min.	Max.
A	31.30	31.65	M	12.00	13.00
B	7.80	8.40	N	25.15	25.65
C	4.00	4.30	O	1.95	2.15
D	∅4.00	∅4.30	P	5.60	6.60
E	4.00	4.30	Q	25.30	26.30
F	14.90	15.20	R	3.90	4.30
G	30.10	30.30	S	4.45	4.85
H	38.00	38.50	T	24.50	25.10
J	12.10	12.90	U	0.05	0.10
K	9.00	9.60	V	3.00	4.80
L	0.75	0.85	W	19.30	20.50

$V_{DSS}=1000V$

$I_{D25}=38A$

$R_{DS(ON)} \leq 0.250\Omega$



Symbol	Test Conditions	Maximum Ratings	Unit
V_{DSS}	$T_J=25^\circ C$ to $150^\circ C$	1000	V
V_{DGR}	$T_J=25^\circ C$ to $150^\circ C$; $R_{GS}=1M\Omega$	1000	V
V_{GS}	Continuous	± 30	V
V_{GSM}	Transient	± 40	V
I_{D25}	$T_C=25^\circ C$	38	A
I_{D25}	$T_C=90^\circ C$	19	A
I_{DM}	$T_C=25^\circ C$; pulse width limited by T_{JM}	160	A
I_{AR}	$T_C=25^\circ C$	38	A
E_{AR}	$T_C=25^\circ C$	60	mJ
dv/dt	$I_S \leq I_{DM}$; $di/dt \leq 100A/us$; $V_{DD} \leq V_{DSS}$ $T_{JS} \leq 150^\circ C$; $R_G=2\Omega$	20000	V/us
P_D	$T_C=25^\circ C$	900	W
T_J		-55...+150	°C
T_{JM}		150	
T_{stg}		-55...+150	
V_{ISOL}	50/60Hz,RMS $t=1$ min $I_{ISOL} \leq 1mA$ $t=1$ s	2500 3000	V~
M_d	Mounting torque Terminal connection torque	1.5/13 1.5/13	Nm/lb.in.
Weight	typical	30	g



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(T_J=25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
V _{DSS}	V _{GS} =0V; I _D =1 mA	1000			V
V _{GS(th)}	V _{DS} =V _{GS} ; I _D =8 mA	3		5.5	V
I _{GSS}	V _{GS} =±20V _{DC} ; V _{DS} =0			±100	nA
I _{DSS}	V _{DS} =0.8V _{DSS} ; T _J =25°C V _{GS} =0V; T _J =125°C		50	20	μA μA
R _{DS(on)}	V _{GS} =10V; I _D =0.5I _{D25} Pulse test, t≤300μs, duty cycle d≤2%			0.250	Ω

(T_J=25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
g _{ts}	V _{DS} =10V; I _D =0.5I _{D25} ; pulse test	24	40		S
C _{ies}	V _{GS} =0V; V _{DS} =25V; f=1MHz		13500		pF
C _{oes}			1030		
C _{res}			185		
Q _{g(on)}	V _{GS} =10V; V _{DS} =0.5V _{DSS} ; I _D =0.5I _{D25}		250		nC
Q _{gs}			58		
Q _{gd}			105		
t _{d(on)}	V _{GS} =10V; V _{DS} =0.5V _{DSS} ; I _D =0.5I _{D25} R _G =1Ω (External)		25		ns
t _r			28		ns
t _{d(off)}			57		ns
t _f			15		ns
R _{thJC}				0.14	K/W
R _{thCK}			0.05		K/W

Source-Drain Diode

(T_J=25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
I _S	V _{GS} =0V			38	A
I _{SM}	Repetitive; pulse width limited by T _{JM}			160	A
V _{SD}	I _F =I _S ; V _{GS} =0V; Pulse test, t≤300μs, duty cycle d≤2%			1.4	V

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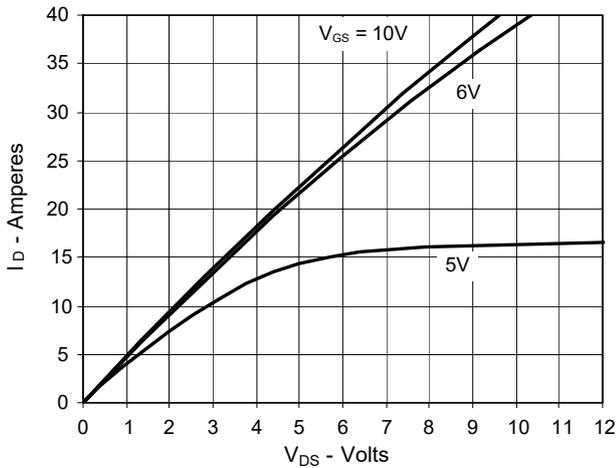


Fig. 1. Output Characteristics @ 25°C

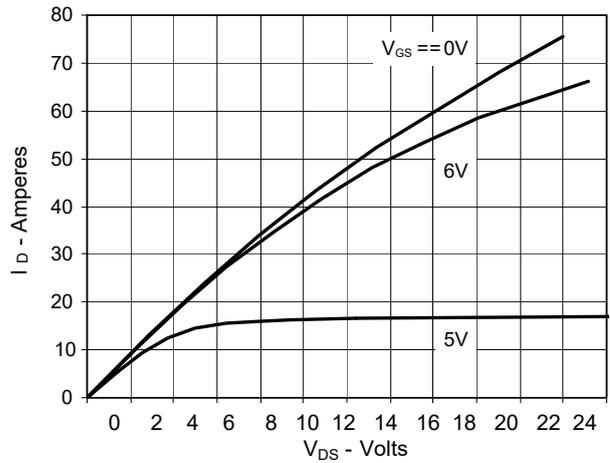


Fig. 2. Extended Output Characteristics @ 25°C

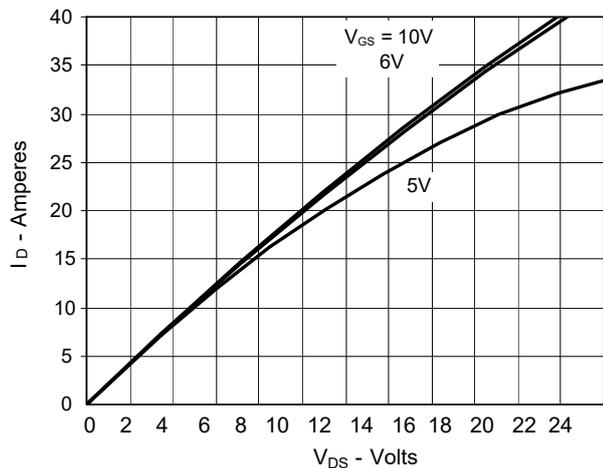


Fig. 3. Output Characteristics @ 125°C

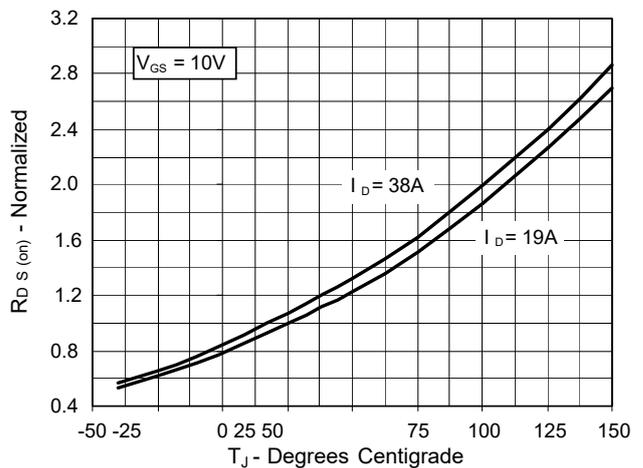


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 19A$ Value vs. Junction Temperature

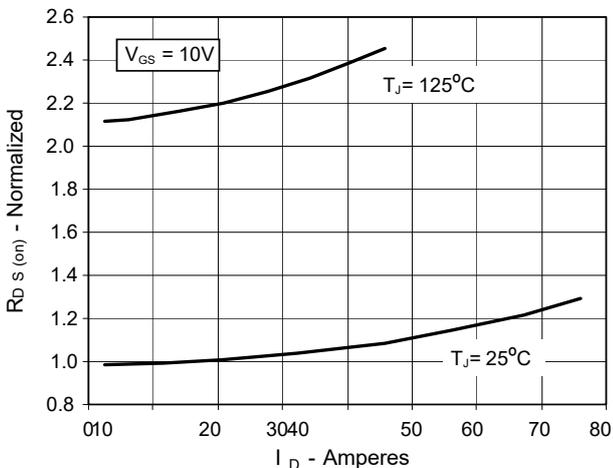


Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 19A$ Value vs. Drain Current

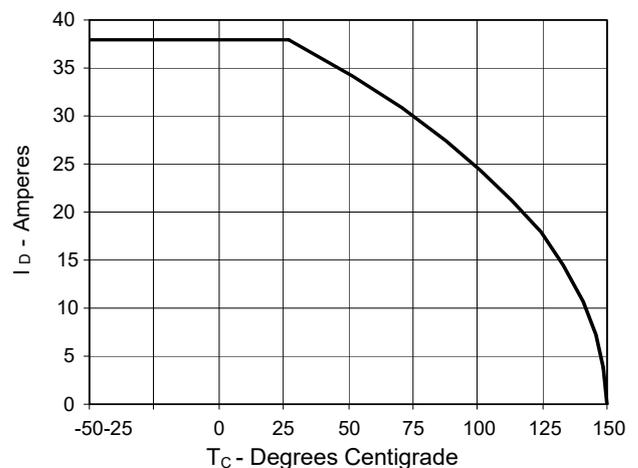


Fig. 6. Drain Current vs. Case Temperature

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N Channel Enhancement Mode Power MOSFETs

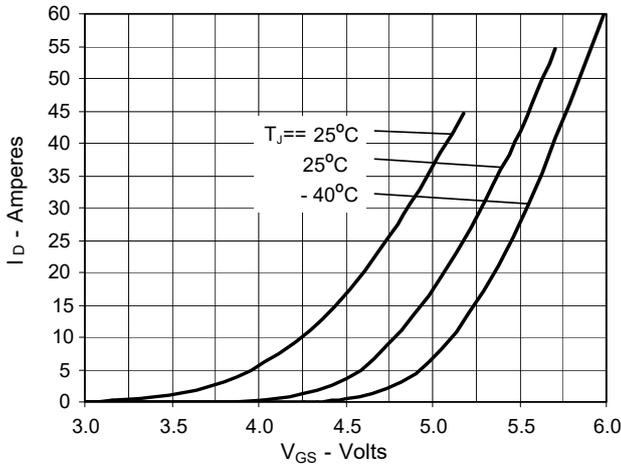


Fig. 7. Input Admittance

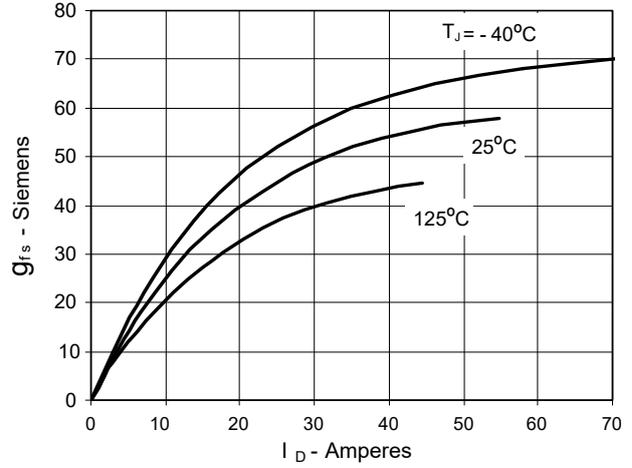


Fig. 8. Transconductance

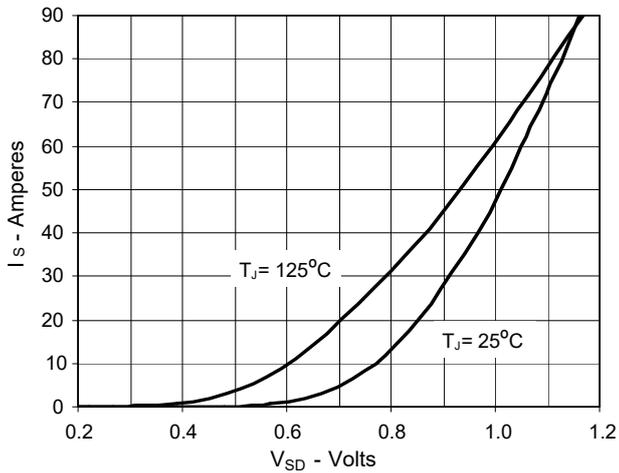


Fig. 9. Source Current vs. Source-To-Drain Voltage

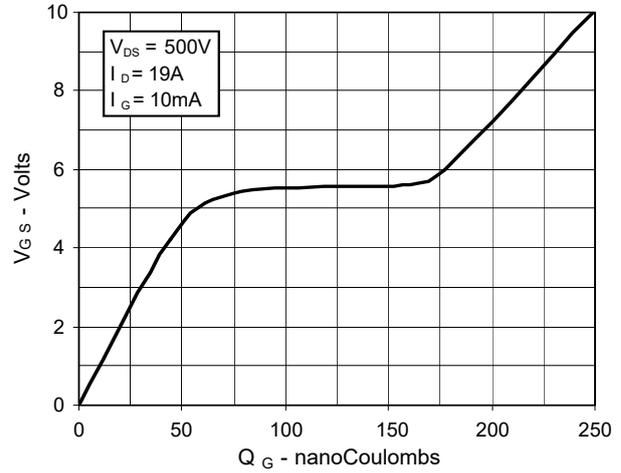


Fig. 10. Gate Charge

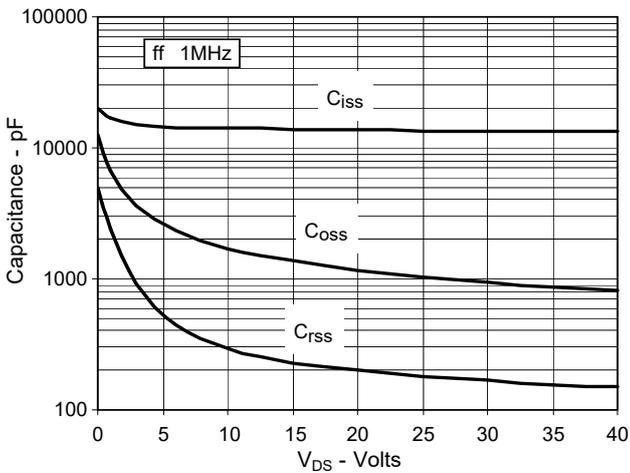


Fig. 11. Capacitance

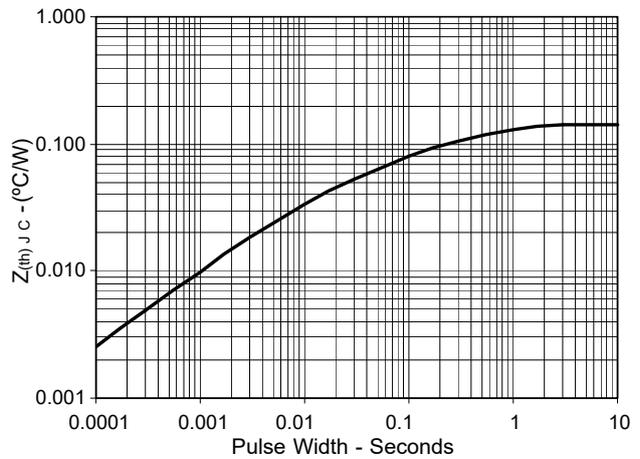


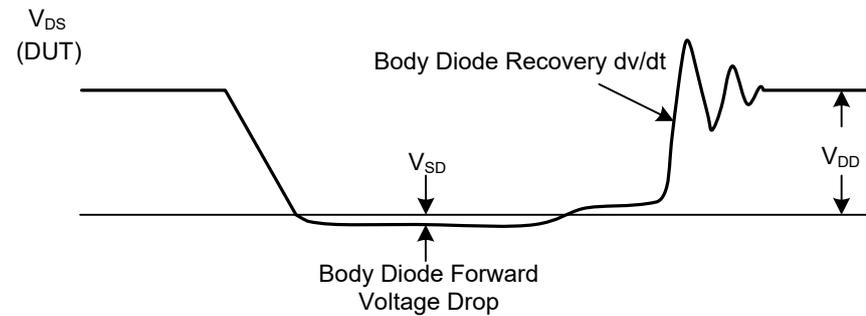
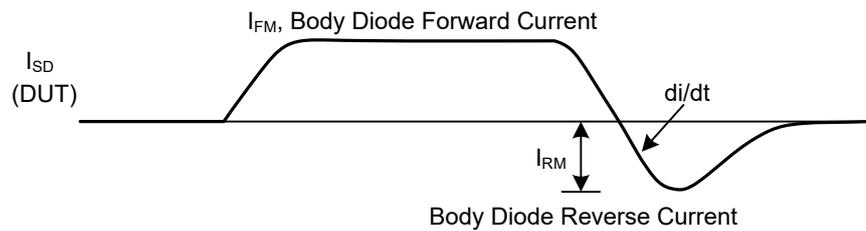
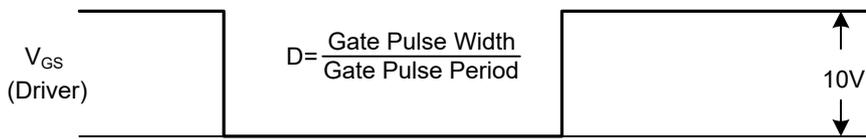
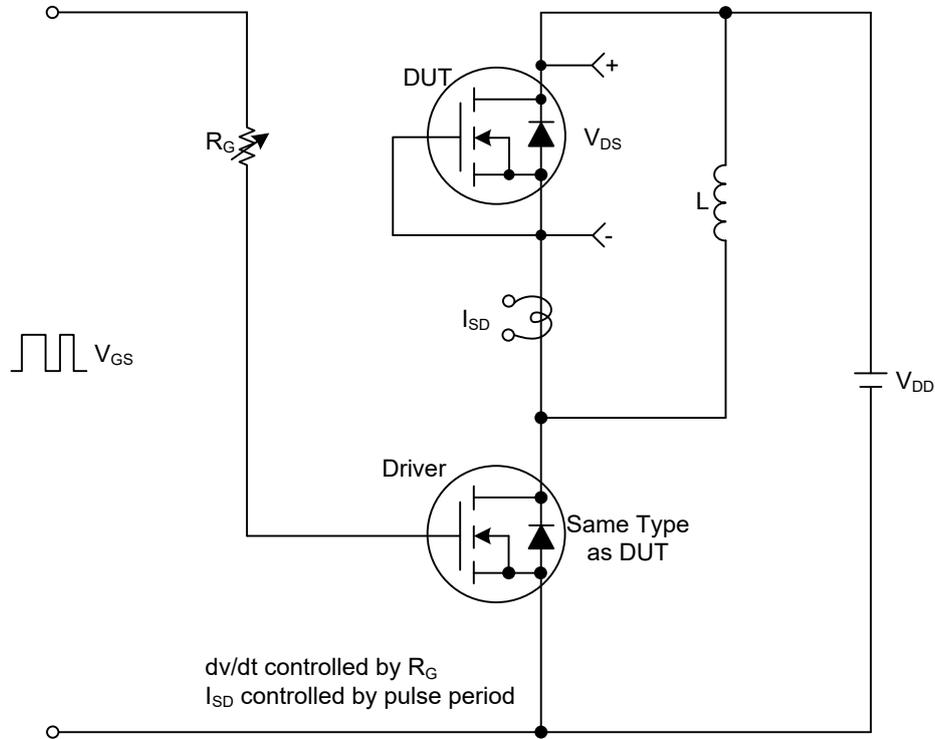
Fig. 12. Maximum Transient Thermal Impedance

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TEST CIRCUITS AND WAVEFORMS

Peak Diode Recovery dv/dt Test Circuit & Waveforms



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